# **MOSFET** - Power, Single, N-Channel, SO-8FL 30 V, 155 A

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Devices

#### **Applications**

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

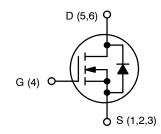
Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Vo	Gate-to-Source Voltage			±20	V
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	25	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 85°C		18	
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.31	W
Continuous Drain	1	T <sub>A</sub> = 25°C	I <sub>D</sub>	40	Α
Current R <sub>θJA</sub> ≤ 10 sec		T <sub>A</sub> = 85°C		29	
Power Dissipation $R_{\theta JA,} t \leq 10 \text{ sec}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	5.95	W
Continuous Drain Current R <sub>BJA</sub>	State	T <sub>A</sub> = 25°C	Ι <sub>D</sub>	16	Α
(Note 2)		T <sub>A</sub> = 85°C		11	
Power Dissipation $R_{\theta JA}$ (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.90	W
Continuous Drain Current Rauc	]	T <sub>C</sub> = 25°C	Ι <sub>D</sub>	155	Α
(Note 1)		T <sub>C</sub> = 85°C		112	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	86.2	W
Pulsed Drain Current	t <sub>p</sub> =10μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	310	Α
Current limited by package $T_A = 25^{\circ}C$			I <sub>Dmaxpkg</sub>	100	Α
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	–55 to +150	°C	
Source Current (Body Diode)			I <sub>S</sub>	72	Α
Drain to Source dV/dt			dV/dt	6	V/ns



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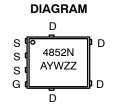
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	2.1 mΩ @ 10 V	155 A
	3.3 mΩ @ 4.5 V	155 A



**N-CHANNEL MOSFET** 



## **SO-8 FLAT LEAD** CASE 488AA STYLE 1



**MARKING** 

Α = Assembly Location

= Year W = Work Week ZZ = Lot Traceability

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4852NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4852NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

Parameter	Symbol	Value	Unit
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 50 V, $V_{GS}$ = 10 V, $I_L$ = 49 $A_{pk}$ , $L$ = 0.3 mH, $R_G$ = 25 $\Omega$ )	EAS	360	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)	TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.45	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	54	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	138.7	*C/VV
Junction-to-Ambient - t ≤ 10 sec	$R_{ heta JA}$	21	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
  Surface-mounted on FR4 board using the minimum recommended pad size.

## **ELECTRICAL CHARACTERISTICS** (T.I = 25°C unless otherwise specified)

Parameter	Symbol	Test Cond	ition	Min	Тур	Max	Unit
OFF CHARACTERISTICS					ı	ı	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				17		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			1	
		V <sub>DS</sub> = 24 V	T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	<sub>S</sub> = ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.45	1.8	2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.9		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		1.6	2.1	mΩ
			I <sub>D</sub> = 15 A		1.6		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		2.4	3.3	
			I <sub>D</sub> = 15 A		2.4		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			47		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				4970		
Output Capacitance	Coss	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V			970		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				427		1
Total Gate Charge	Q <sub>G(TOT)</sub>				34.3	48	
Threshold Gate Charge	Q <sub>G(TH)</sub>	V 45VV	15 \		4.2		nC
Gate-to-Source Charge	$Q_{GS}$	$V_{GS}$ = 4.5 V, $V_{DS}$ =	15 V; I <sub>D</sub> = 30 A		13		
Gate-to-Drain Charge	$Q_{GD}$	1			11.3		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A			71.3		nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t <sub>d(ON)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V,			21.1		
Rise Time	t <sub>r</sub>				25.6		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 15 \text{ A}, R_G = 3.0 \Omega$			35		ns

- 3. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
- 4. Switching characteristics are independent of operating junction temperatures.

Fall Time

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)				•		
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			12		- ns
Rise Time	t <sub>r</sub>				19		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				50		
Fall Time	t <sub>f</sub>				7.7		
DRAIN-SOURCE DIODE CHARACTI	ERISTICS						
Forward Diode Voltage	$V_{SD}$	VGS - UV,	T <sub>J</sub> = 25°C		0.8	1.2	
			T <sub>J</sub> = 125°C		0.61		_ V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A}/\mu\text{s,}$ $I_{S} = 30 \text{ A}$			35		
Charge Time	t <sub>a</sub>				17		ns
Discharge Time	t <sub>b</sub>				18		
Reverse Recovery Charge	Q <sub>RR</sub>				28.6		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.65		nΗ
Drain Inductance	L <sub>D</sub>				0.005		
Gate Inductance	L <sub>G</sub>				1.84		
Gate Resistance	$R_{G}$				1.0	2.0	Ω

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

## **TYPICAL CHARACTERISTICS**

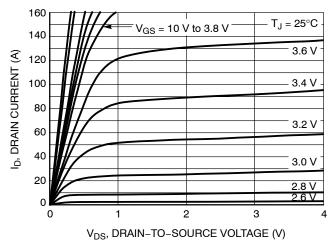


Figure 1. On-Region Characteristics

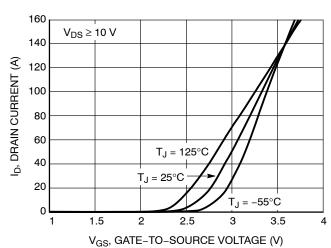


Figure 2. Transfer Characteristics

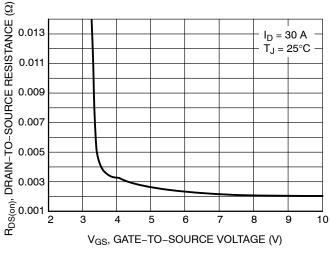


Figure 3. On-Resistance vs. Gate-to-Source Voltage

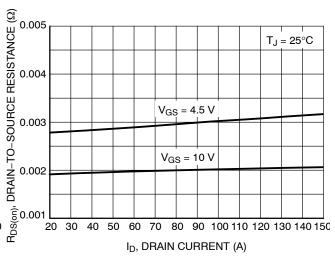


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

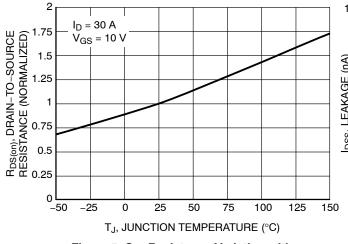


Figure 5. On–Resistance Variation with Temperature

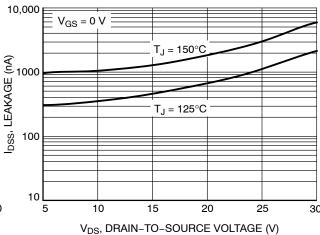


Figure 6. Drain-to-Source Leakage Current vs. Voltage

## TYPICAL CHARACTERISTICS

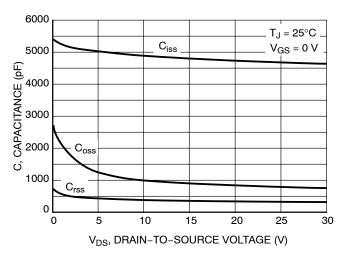


Figure 7. Capacitance Variation

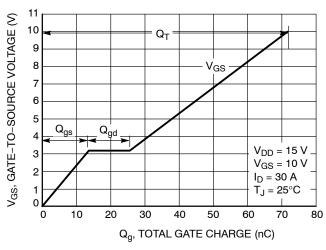


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

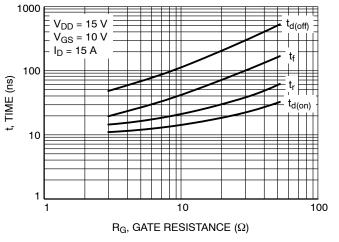


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

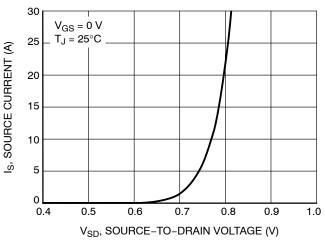


Figure 10. Diode Forward Voltage vs. Current

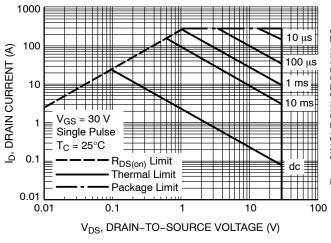


Figure 11. Maximum Rated Forward Biased Safe Operating Area

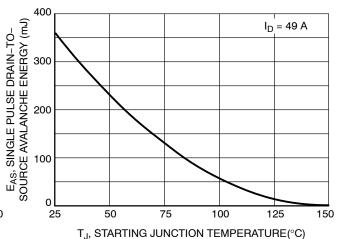


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

## **TYPICAL CHARACTERISTICS**

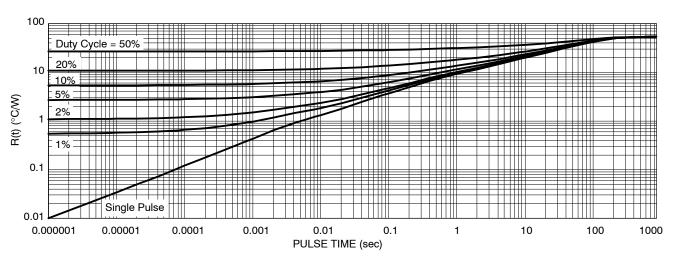
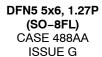
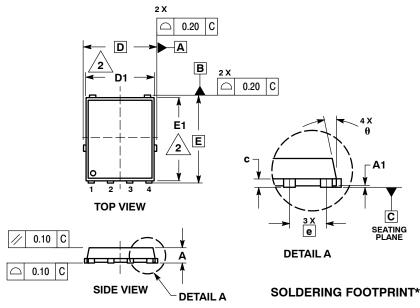


Figure 13. Thermal Response

#### PACKAGE DIMENSIONS



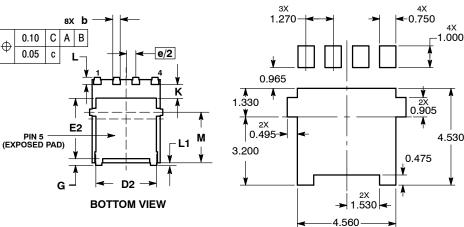


#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.90	1.00	1.10		
A1	0.00		0.05		
b	0.33	0.41	0.51		
С	0.23	0.28	0.33		
D		5.15 BSC	;		
D1	4.50	4.90	5.10		
D2	3.50		4.22		
E		6.15 BSC			
E1	5.50	5.80	6.10		
E2	3.45		4.30		
е		1.27 BSC	;		
G	0.51	0.61	0.71		
K	1.20	1.35	1.50		
L	0.51	0.61	0.71		
L1	0.05	0.17	0.20		
M	3.00	3.40	3.80		
θ	0 °		12 °		

- STYLE 1: PIN 1. SOURCE
  - SOURCE
    SOURCE
  - GATE
  - 5. DRAIN



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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